

June 2009

# **FDMC8200**

# Dual N-Channel PowerTrench<sup>®</sup> MOSFET 30 V, 9.5 m $\Omega$ and 20 m $\Omega$

### **Features**

Q1: N-Channel

- Max  $r_{DS(on)}$  = 20 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 6 A
- Max  $r_{DS(on)}$  = 32 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 5 A

Q2: N-Channel

- Max  $r_{DS(on)} = 9.5 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 9 \text{ A}$
- Max  $r_{DS(on)} = 13.5 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 7 \text{ A}$
- RoHS Compliant

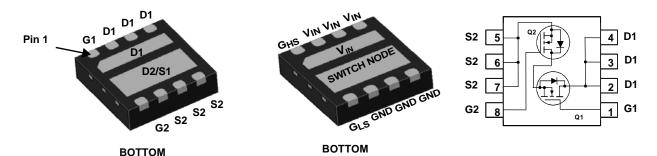


### **General Description**

This device includes two specialized N-Channel MOSFETs in a dual Power33 (3mm x 3mm MLP) package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q1) and synchronous MOSFET (Q2) have been designed to provide optimal power efficiency.

### **Applications**

- Mobile Computing
- Mobile Internet Devices
- General Purpose Point of Load



Power 33

### MOSFET Maximum Ratings T<sub>C</sub> = 25 ℃ unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V <sub>DS</sub>	Drain to Source Voltage		30	30	V
V <sub>GS</sub>	Gate to Source Voltage	(Note 3)	±20	±20	V
	Drain Current - Continuous (Package limited)	T <sub>C</sub> = 25 ℃	18	18	
- Contin	- Continuous (Silicon limited)	T <sub>C</sub> = 25 ℃	23	45	^
	- Continuous	T <sub>A</sub> = 25 ℃	8 <sup>1a</sup>	12 <sup>1b</sup>	A
	- Pulsed		40	40	
D	Power Dissipation	T <sub>A</sub> = 25 ℃	1.9 <sup>1a</sup>	2.2 <sup>1b</sup>	10/
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 ℃	0.7 <sup>1c</sup>	0.9 <sup>1d</sup>	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to	+150	C

### Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	65 <sup>1a</sup>	55 <sup>1b</sup>	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient 180		145 <sup>1d</sup>	C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		4	

### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC8200	FDMC8200	Power 33	13 "	12 mm	3000 units

# **Electrical Characteristics** $T_J = 25 \text{ } \text{C}$ unless otherwise noted

Symbol	Parameter Test Conditions		Type	Min	Тур	Max	Units
Off Chara	cteristics						
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$ $I_D = 250 \mu A, V_{GS} = 0 V$	Q1 Q2	30 30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, referenced to 25 °C $I_D$ = 250 μA, referenced to 25 °C	Q1 Q2		14 14		mV/℃
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V	Q1 Q2			1 1	μА
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V	Q1 Q2			100 100	nA nA

### **On Characteristics**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, \ I_D = 250 \ \mu A$ $V_{GS} = V_{DS}, \ I_D = 250 \ \mu A$	Q1 Q2	1.0 1.0	2.3 2.3	3.0 3.0	V	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 μA, referenced to 25 °C $I_D$ = 250 μA, referenced to 25 °C	Q1 Q2		-5 -6		mV/℃	
-		$V_{GS} = 10 \text{ V}, I_D = 6 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 5 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 6 \text{ A}, T_J = 125 \text{ C}$	Q1		16 24 22	20 32 28		
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, \ I_D = 9 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \ I_D = 7 \text{ A}$ $V_{GS} = 10 \text{ V}, \ I_D = 9 \text{ A}, \ T_J = 125 ^{\circ}\text{C}$	Q2		7.3 9.5 10	9.5 13.5 13	mΩ	
g <sub>FS</sub>	Forward Transconductance	$V_{DD} = 5 \text{ V}, I_D = 6 \text{ A}$ $V_{DD} = 5 \text{ V}, I_D = 9 \text{ A}$	Q1 Q2		29 56		S	

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance		Q1 Q2	495 1180	660 1570	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1 MHZ	Q1 Q2	145 330	195 440	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		Q1 Q2	20 30	30 45	pF
R <sub>g</sub>	Gate Resistance		Q1 Q2	1.4 1.4		Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time	Q1				11 13	20 23	ns
t <sub>r</sub>	Rise Time		$V_{DD} = 15 \text{ V, } I_{D} = 1 \text{ A,}$ $V_{GS} = 10 \text{ V, } R_{GEN} = 6 \Omega$			3.1 4	10 10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	Q2 V <sub>DD</sub> = 15 V, I <sub>D</sub> = 1 A	Δ	Q1 Q2		35 38	56 60	ns
t <sub>f</sub>	Fall Time	00	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$			1.3 6	10 12	ns
Q <sub>g(TOT)</sub>	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V		Q1 Q2		7.3 16	10 22	nC
Q <sub>g(TOT)</sub>	Total Gate Charge	V <sub>GS</sub> = 0 V to 4.5 V	$V_{DD} = 15 \text{ V},$ $I_{D} = 6 \text{ A},$	Q1 Q2		3.1 7	4.3 10	nC
Q <sub>gs</sub>	Gate to Source Charge		Q2: V <sub>DD</sub> = 15 V,	Q1 Q2		1.8 4.1		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		$I_{D} = 9 \text{ A},$	Q1 Q2		1 1.5		nC

Max Units

# 

Parameter

Drain-Source Diode Characteristics								
V	Source to Drain Diode Forward Volt-	$V_{GS} = 0 \text{ V}, I_{S} = 6 \text{ A}$	(Note 2)	Q1		0.8	1.2	\/
$V_{SD}$	age	$V_{GS} = 0 \text{ V}, I_{S} = 6 \text{ A}$ $V_{GS} = 0 \text{ V}, I_{S} = 9 \text{ A}$	(Note 2)	Q2		0.8	1.2	V
+	Poverse Possvery Time	Q1		Q1		13	24	nc
'rr	Reverse Recovery Time	$I_F = 6 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		Q2		21	34	ns
0	Poverse Possivery Charge	Q2		Q1		2.3	10	nC
Q <sub>rr</sub>	Reverse Recovery Charge	$I_F = 9 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		Q2		5.6	12	110

**Test Conditions** 

#### Notes

Symbol

1. R<sub>0JA</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a.65 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper

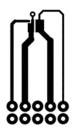


b.55 °C/W when mounted on a 1 in² pad of 2 oz copper

Type

Min

Тур



c. 180 °C/W when mounted on a minimum pad of 2 oz copper



d. 145 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.
- 3. As an N-ch device, the negative Vgs rating is for low duty cycle pulse ocurrence only. No continuous rating is implied.

### Typical Characteristics (Q1 N-Channel) T<sub>J</sub> = 25 °C unless otherwise noted

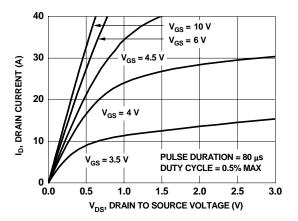


Figure 1. On Region Characteristics

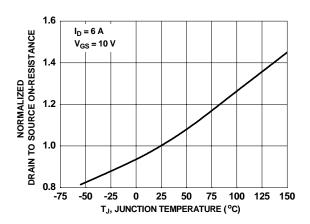


Figure 3. Normalized On Resistance vs Junction Temperature

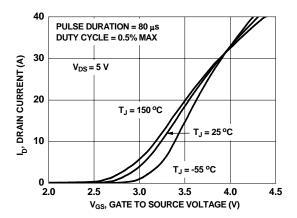


Figure 5. Transfer Characteristics

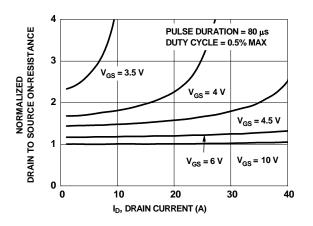


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

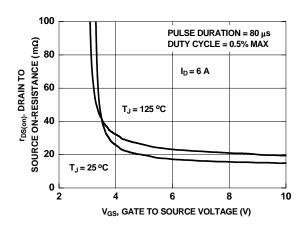


Figure 4. On-Resistance vs Gate to Source Voltage

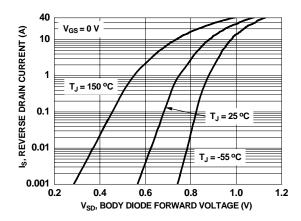


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

### Typical Characteristics (Q1 N-Channel) T<sub>J</sub> = 25 °C unless otherwise noted

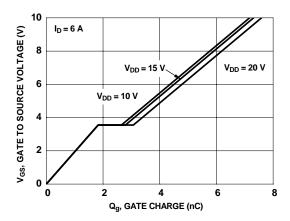


Figure 7. Gate Charge Characteristics

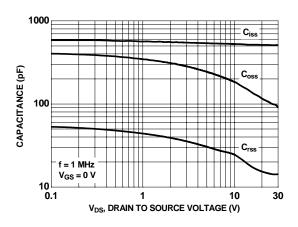


Figure 8. Capacitance vs Drain to Source Voltage

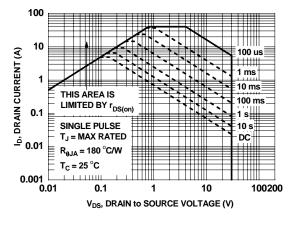


Figure 9. Forward Bias Safe Operating Area

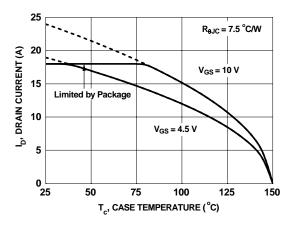


Figure 10. Maximum Continuous Drain Current vs Case Temperature

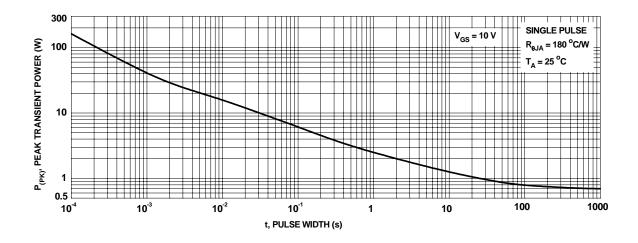


Figure 11. Single Pulse Maximum Power Dissipation

# Typical Characteristics (Q1 N-Channel) $T_J = 25 \text{ } \text{C}$ unless otherwise noted

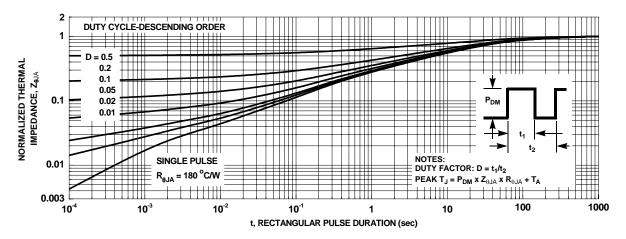


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

### Typical Characteristics (Q2 N-Channel) T<sub>J</sub> = 25 ℃ unless otherwise noted

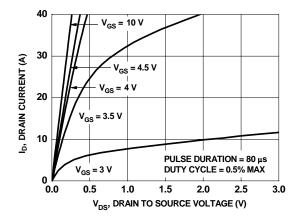


Figure 13. On-Region Characteristics

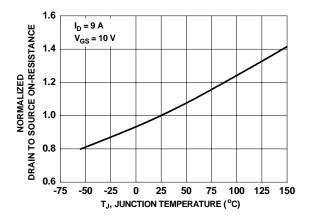


Figure 15. Normalized On-Resistance vs Junction Temperature

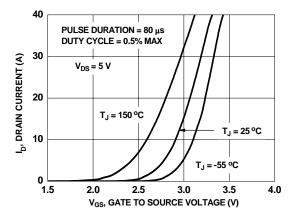


Figure 17. Transfer Characteristics

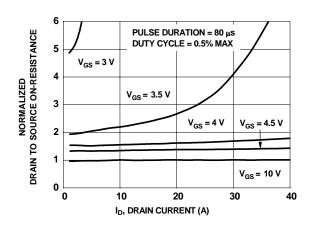


Figure 14. Normalized on-Resistance vs Drain Current and Gate Voltage

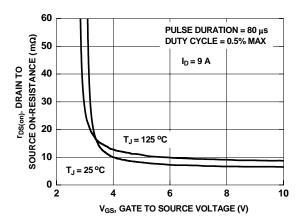


Figure 16. On-Resistance vs Gate to Source Voltage

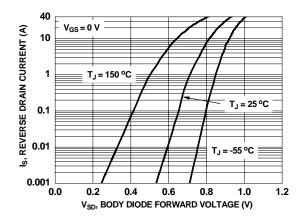


Figure 18. Source to Drain Diode Forward Voltage vs Source Current

### Typical Characteristics (Q2 N-Channel) T<sub>J</sub> = 25 ℃ unless otherwise noted

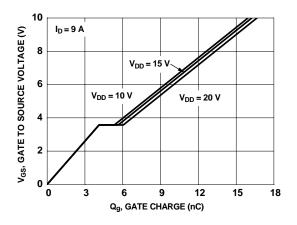


Figure 19. Gate Charge Characteristics

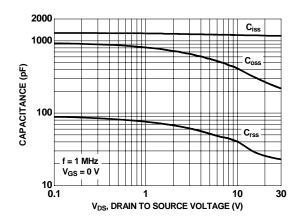


Figure 20. Capacitance vs Drain to Source Voltage

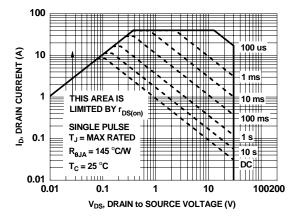


Figure 21. Forward Bias Safe Operating Area

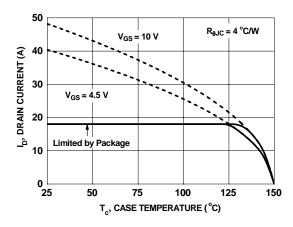


Figure 22. Maximum Continuous Drain Current vs Case Temperature

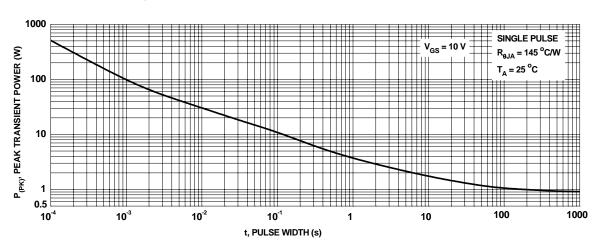


Figure 22. Single Pulse Maximum Power Dissipation

# Typical Characteristics (Q2 N-Channel) $T_J = 25 \text{ } \text{C}$ unless otherwise noted

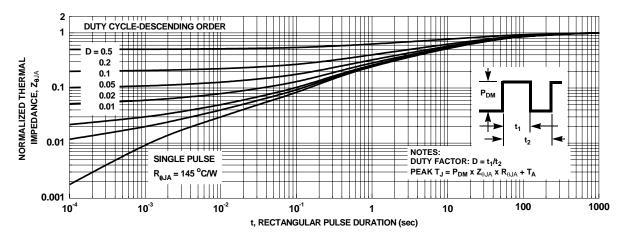
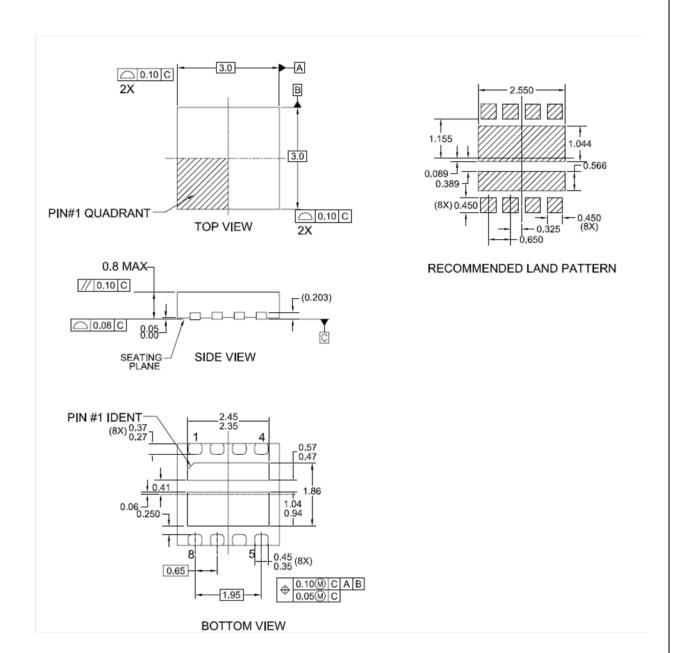


Figure 23. Junction-to-Ambient Transient Thermal Response Curve

## **Dimensional Outline and Pad Layout**







#### TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

Auto-SPM™ Build it Now™ CorePLUS™ CorePOWER™ CROSSVOLT™ CTI ™

Current Transfer Logic™ EcoSPARK<sup>®</sup>  $\mathsf{EfficentMax}^{\mathsf{TM}}$ EZSWITCH™ \*

Fairchild<sup>®</sup>

Fairchild Semiconductor® FACT Quiet Series™

FACT FAST® FastvCore™ FFTBench™ FlashWriter® \* **FPSTM** 

FRFET®

Global Power Resource<sup>SM</sup> Green FPS™

Green FPS™ e-Series™ Gmax™ GTO™

IntelliMAX™ ISOPLANAR™ MegaBuck™ MICROCOUPLER™ MicroFET™ MicroPak™  $\mathsf{MillerDrive}^{\mathsf{TM}}$ MotionMax™

OPTOPLANAR®

Motion-SPM™

OPTOLOGIC®

PDP SPM™ Power-SPM™ PowerTrench® PowerXS<sup>™</sup>

Programmable Active Droop™

OFFT<sup>®</sup> QSTM Quiet Series™

RapidConfigure™

Saving our world, 1mW /W /kW at a time™

SmartMax™ SMART START™ SPM® STEALTH™ SuperFET™

SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS™ SyncFET™ Sync-Lock™

SYSTEM ® GENERAL

The Power Franchise® puwer' TinyBoost™ TinyBuck™ TinyLogic® TIŃYOPTO™ TinyPower™ TinyPWM™ TinyWire™ TriÉault Detect™ TRUECURRENT™\* μSerDes™

UHC® Ultra FRFET™ UniFET™ VCX™ VisualMax™ XS™

\*Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

#### DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

**LIFE SUPPORT POLICY**FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness

#### ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

#### PRODUCT STATUS DEFINITIONS **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information Formative / In Design		Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. 140